

UNITED STATES PATENT AND TRADEMARK
BEFORE THE PATENT TRIAL AND APPEAL

IMPINJ, INC.,
Petitioner

V.
NXP B.V.
Patent Owner

IPR2020-01630

U.S. Patent No. 6,680,523





Petitioner Did Not Demonstrate That Any Cl

- Impinj failed to provide viable construction for “module.” P.O. Sur-Reply at 1-8.
- Impinj failed to show that Yamaguchi anticipated obvious any claim of the '523 patent under P.O. Resp. at 14-31.
- Impinj failed to show that Satya anticipates claim of the '523 patent under NXP's construction 31-51.
- The Board previously rejected the combination of Satya, and Impinj has not provided any additional evidence that Ground. P.O. Resp. at 52-54.



The '523 Patent (“So

U.S. Patent No. 6,680,523 ("Schober")


US006680523B2

(12) **United States Patent**
Schober et al.

(10) Patent No.: **US 6,680,523 B2**
(45) Date of Patent: **Jan. 20, 2004**

(54) **SEMICONDUCTOR WAFER WITH PROCESS CONTROL MODULES**

(70) Inventors: **Joachim H. Schober**, Monberggasse 6/2, A-8010 Graz (AT); **Helmo Scheucher**, Kogelbuchstrasse 23, A-8030 Langegg (AT); **Paul Hofner**, Alte Poststrasse 57/9, A-8020 Graz (AT)

(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 0 days.

(21) Appl. No.: **10/081,893**
(22) Filed: **Feb. 21, 2002**
(65) **Prior Publication Data**
US 2002/0117735 A1 Aug. 29, 2002
(30) **Foreign Application Priority Data**
Feb. 27, 2001 (EP) 01809020
(51) Int. Cl.⁷ H01L 23/544

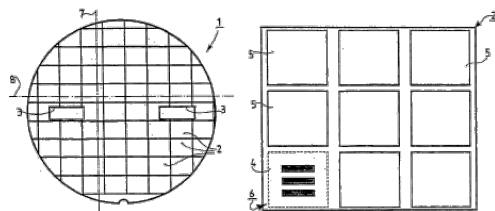
(52) U.S. Cl. 257/620; 257/48
(58) Field of Search 257/620, 48

(56) **References Cited**
U.S. PATENT DOCUMENTS
5,328,737 A * 7/1993 van der Horst 257/603
5,990,488 A 11/1999 Nisler et al. 257/48

* cited by examiner
Primary Examiner—David L. Tidd
Assistant Examiner—Lynn Thai
(74) Attorney, Agent, or Firm—Steven R. Birn

(57) **ABSTRACT**
A semiconductor wafer (1) has a multitude of chips (5), of which chips (5) each one of a given number of chips (5) is situated in one of a multitude of adjacent exposure fields (2), and further has process control modules (4) which are each arranged in an exposure field (2), namely each in place of at least one chip (5).

4 Claims, 1 Drawing Sheet



(12) **United States Patent**
Schober et al.

(54) **SEMICONDUCTOR**
CONTROL MODUL

(21) Appl. No.: **10/081,893**

(22) Filed: **Feb. 21, 2002**


(65) **Prior Publ**

US 2002/0117735 A1 Au

(30) **Foreign Applica**

Feb. 27, 2001 (EP)

Figures and Abstract of Schober



US006680523B2

(12) **United States Patent**
Schober et al.

(10) Patent No.: **US 6,680,523 B2**
(45) Date of Patent: **Jan. 20, 2004**

(54) **SEMICONDUCTOR WAFER WITH PROCESS CONTROL MODULES**

(70) Inventors: **Joachim H. Schober**, Monberggasse 6/2, A-8010 Graz (AT); **Helmo Scheuchner**, Kogelbuchstrasse 23, A-8030 Langegg (AT); **Paul Hehner**, Alte Poststrasse 57/9, A-8020 Graz (AT)

(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 0 days.

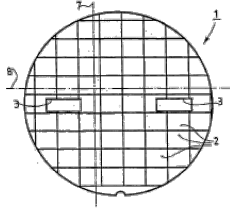
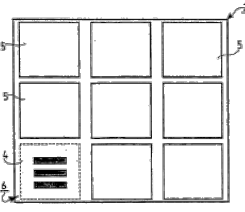
(21) Appl. No.: **10/081,893**
(22) Filed: **Feb. 21, 2002**
(65) **Prior Publication Data**
US 2002/011735 A1 Aug. 29, 2002
(30) **Foreign Application Priority Data**
Feb. 27, 2001 (EP) 01809020
(51) Int. Cl.⁷ H01L 23/544

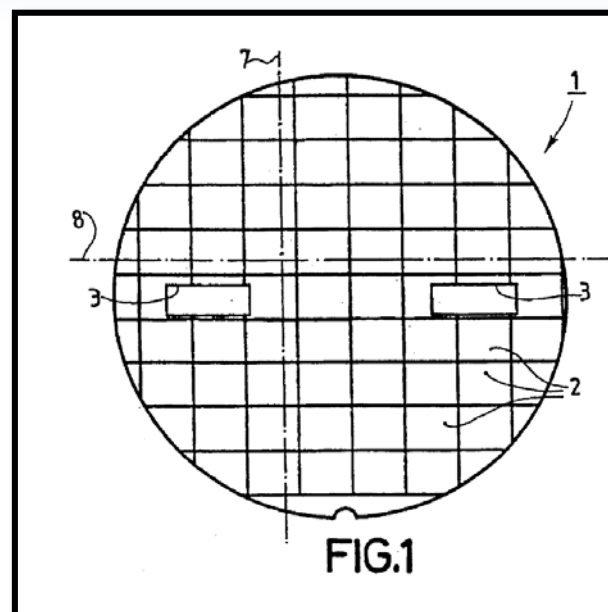
(52) U.S. Cl. **257/620; 257/48**
(58) Field of Search **257/620, 48**

(56) **References Cited**
U.S. PATENT DOCUMENTS
5,328,737 A * 7/1993 van der Horst 257/603
5,990,488 A 11/1999 Nisler et al. 257/48
* cited by examiner
Primary Examiner—David L. Tidd
Assistant Examiner—Lynn Thai
(74) **Attorney, Agent, or Firm**—Steven R. Birn

(57) **ABSTRACT**
A semiconductor wafer (1) has a multitude of chips (5), of which chips (5) each one of a given number of chips (5) is situated in one of a multitude of adjacent exposure fields (2), and further has process control modules (4) which are each arranged in an exposure field (2), namely each in place of at least one chip (5).

4 Claims, 1 Drawing Sheet



(57)

AI

A semiconductor wafer (1) which chips (5) each one situated in one of a multitude and further has process co arranged in an exposure fi

Explore Litigation Insights

Docket Alarm provides insights to develop a more informed litigation strategy and the peace of mind of knowing you're on top of things.

Real-Time Litigation Alerts



Keep your litigation team up-to-date with **real-time alerts** and advanced team management tools built for the enterprise, all while greatly reducing PACER spend.

Our comprehensive service means we can handle Federal, State, and Administrative courts across the country.

Advanced Docket Research



With over 230 million records, Docket Alarm's cloud-native docket research platform finds what other services can't. Coverage includes Federal, State, plus PTAB, TTAB, ITC and NLRB decisions, all in one place.

Identify arguments that have been successful in the past with full text, pinpoint searching. Link to case law cited within any court document via Fastcase.

Analytics At Your Fingertips



Learn what happened the last time a particular judge, opposing counsel or company faced cases similar to yours.

Advanced out-of-the-box PTAB and TTAB analytics are always at your fingertips.

API

Docket Alarm offers a powerful API (application programming interface) to developers that want to integrate case filings into their apps.

LAW FIRMS

Build custom dashboards for your attorneys and clients with live data direct from the court.

Automate many repetitive legal tasks like conflict checks, document management, and marketing.

FINANCIAL INSTITUTIONS

Litigation and bankruptcy checks for companies and debtors.

E-DISCOVERY AND LEGAL VENDORS

Sync your system to PACER to automate legal marketing.